Search Notes



Applica	tion/Co	ntrol No),
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Applicant(s)/Patent Under Reexamination

SCHIFF, LEONARD N.

Examiner

RICHARD CHAN

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
455	12.1, 427, 428, 11.1, 13.1, 13.2,	5/17/11	RC

SEARCH NOTE	ES
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Search Notes	Date	Examiner
Consulted Raymond Dean (Primary) regarding prior art search	1/16/12	RC
Consulted Yuwen Pan for prior art and 112 1st paragraph rejection for claim 28	1/29/12	RC

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